

<b>Notice of References Cited</b>	Application/Control No. 10/767,763	Applicant(s)/Patent Under Reexamination OGAWA, HIDEHIKO	
	Examiner Thomas D. Lee	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,742,769	04-1998	Lee et al.	709/206
*	B	US-7,095,524	08-2006	Ogawa, Hidehiko	358/1.15
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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